Sharad C. Seth
(Curriculum Vitae)

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Professor of Computer Science & Engineering
University of Nebraska-Lincoln

Education

B.E.(Hons.)	Electronics & Telecommunications	1964	Jabalpur, India
M.Tech	Electrical Engineering	1966	I.I.T. Kanpur, India
Ph.D.	Electrical Engineering	1970	U. of Illinois, Urbana-Champaign

Professional Experience

1983 – present, University of Nebraska-Lincoln, Professor, Computer Science & Engineering

1996 – 2003, University of Nebraska-Lincoln, Director, Center for Communication and Information Science (CCIS), Interim during the first year

1998 –2003, University of Nebraska-Lincoln, Coordinator, Research Computing Facility (RCF)

1976 – 1983, University of Nebraska-Lincoln, Associate Professor, Computer Science

1970 – 1976, University of Nebraska-Lincoln, Assistant Professor, Computer Science

Professional Societies: IEEE (Fellow), ACM (Member), VLSI Society of India (Member)

Research

VLSI Testing

Test and Test-point selection in high-volume manufacturing [*ISQED*:236-241 2008, *VTS*:318-324 2007]

Low-power Testing and Test Compaction [*ISCAS'2010*: (Schemm et al.), *VTS'2010*: 307-312, *VDC'2010*: 9-14, Fundamenta *Informaticae*: 2008, *VDC'2005*:491-496, *ATS*:337-342 2005, *ITC*:470-479 2003, *TC* 33(10):934-937 1984]

Random-Pattern Testability and Testability Analysis [*JETTA* 19(3):271-284 2003, *TC* 39(11):582-586 1990, *Integration* 7(1):49-75 1989, *TC* 38(11):1558-1563 1989, *ETC*:139-143 1989, *DFT*:47-52 1988, *FTCS*:318-323 1986, *FTCS*:220-225 1985, *ICCD*:562-656 1985, *ISCAS*:687-690 1985, *ITC*:803-805 1985]

Determining Product Quality from Test Data [*TVLSI* 1(4):537-545 1993, *ITC*:712-720 1990, *TCAD* 3(4):123-126 1986, *JSCC* SC17:57-61 1981, *EDL* 2(11):286-287 1981, *DAC*: 196-203 1981]

Document Image Analysis

Web Table Analysis [*DAS'2010*:
Handwriting and Character Recognition [*LNCS 4768*: 218-230 2008, *ICPR*:99-103 2006, *SPIE 5296:*102-108 2003, *PAMI* 9(5):710-715 1987, *ICPR*:352-355 1986]

XY-Tree Sementation [*ICDAR*:827-831 2001, *ICDAR*:615-618 1995, *Library Hi Tech* 11(3):73-92 1993, *PAMI* 15(7):737-747 1993, *IEEE Computer* 25(7):10-22 1992, *Pattern Recognition in Practice II*:149-159 1986, *ICPR*:347-349 1984]

Map Image Understanding [*IJDAR* 2(4):177-185 2000, *LNCS 1389K*:302-313 1998, *ICDAR*:467-470 1999, *GREC*:268-276 1997, *GIS/LIS*:89-97 1997]

Honors and Awards

IEEE Fellow Award "For contributions to testing of digital electronics circuits", 1997.

Best Poster Paper Award, *3rd International Conference on Document Analysis and Recognition*, 1995.

Honorable Mention Paper Award, *International Conference on VLSI Design*, 1992.

Best Paper Award, Design and Test Category, *International Conference on Computer Design*, 1988.

Best Presentation Paper Award, *International Conference on Computer Design*, 1985.

Teaching

Frquently Taught Courses

Computer Organization, VLSI Design, Microcomputer Applications, Computer Architecture, Professional Development, Senior Design, Fault Tolerant Computing (VLSI Testing)

Organizer and Speaker: Tutorial on "Test Generation for VLSI Circuits", International Test Conference (1987, 88, 89, 90), Design Automation Conference (1989), First European Test Conference (1989), VLSI Design Conference (1992 and 95).

Direction of Graduate Student Research as Major Advisor: 11 PhD and 25 Masters students.

Significant Professional Service

JETTA Editorial Board: 1990 – present; *IEEE Transactions on Computer Aided Design*: Associate Editor 1989-1992; *IEEE Design & Test of Computers*: Editor of Tutorials and Short Papers, 1987-1991; *EIT 2005*: Program Committee Chair;